

**Notic of R ferences Cited**

Application/Control No.

09/542,473

Applicant(s)/Patent Under  
Reexamination  
IKEDA ET AL.

Examiner

A. Sefer

Art Unit

2826

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**NON-PATENT DOCUMENTS**

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	U	Lee et al., "New Polycrystalline Silicon TFT's with Selectively Doped REgion in the Channel" IDW '99
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.